

# Phase and Amplitude Noise Measurements

Fundamentals and Best Practices

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LLRF Workshop 2024 – INFN-LNF, Frascati

29<sup>th</sup> October 2024

HELMHOLTZ



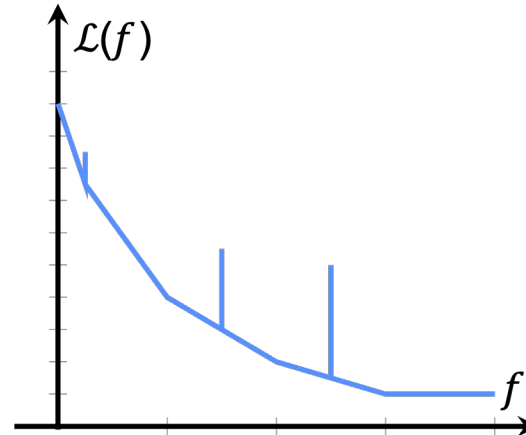
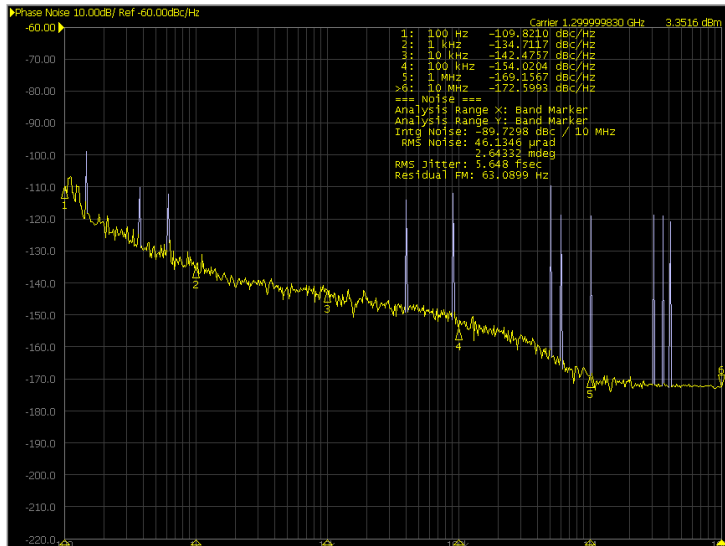
# Talk Overview

The goal of this talk is to understand ...

- Phase & amplitude noise

$$\mathcal{L}(f) = \frac{1}{2} S'_\varphi(f), \quad S_\varphi(f) = \mathbb{E} \left[ \int_{-\infty}^{\infty} R_\varphi(\tau) e^{-i2\pi f\tau} d\tau \right]$$

- Graphical representations



- Measurement techniques & analyser settings

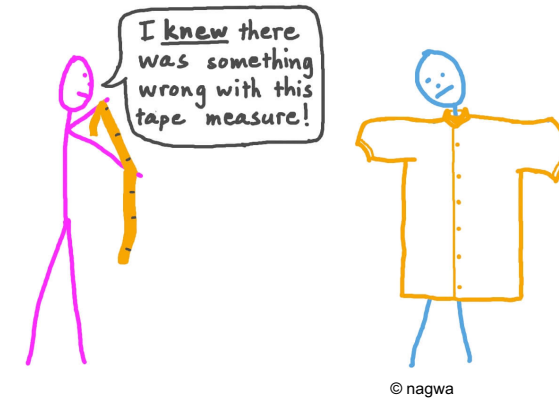


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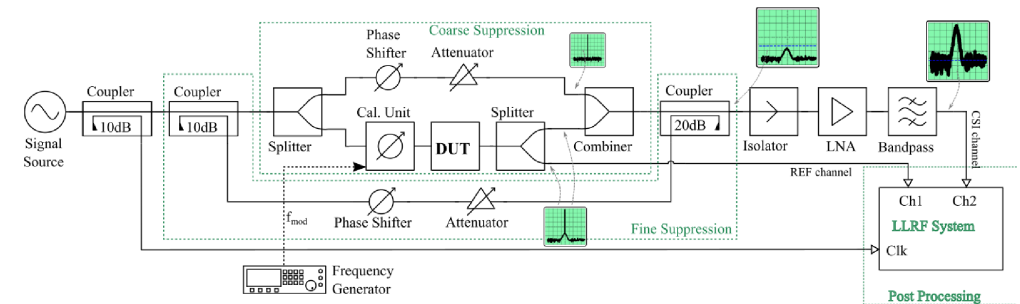


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- Common mistakes and limitations



- Advanced techniques



Courtesy F. Ludwig, M. Hoffmann

# Perspective



**An Overview: Reference Distribution and  
Synchronization Systems  
From Sub-picoseconds to Sub-femtoseconds Stability**

**Marie Kristin Czwalinna**  
(DESY)

Tomorrow – 09:05



**Basics of RF Reference Signal Generation and  
Synchronization Systems**

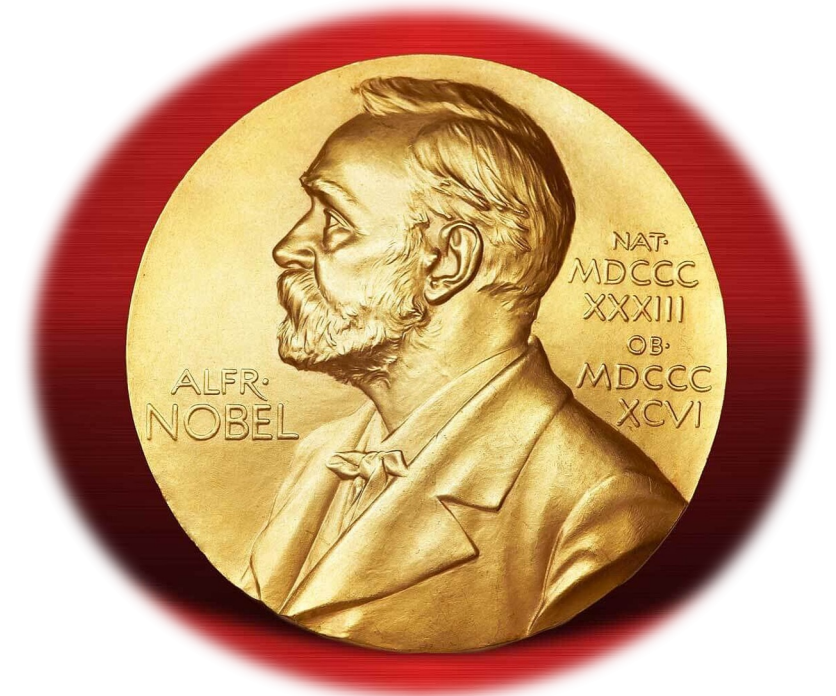
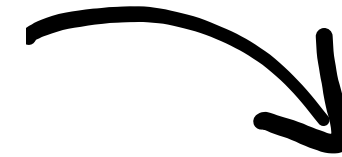
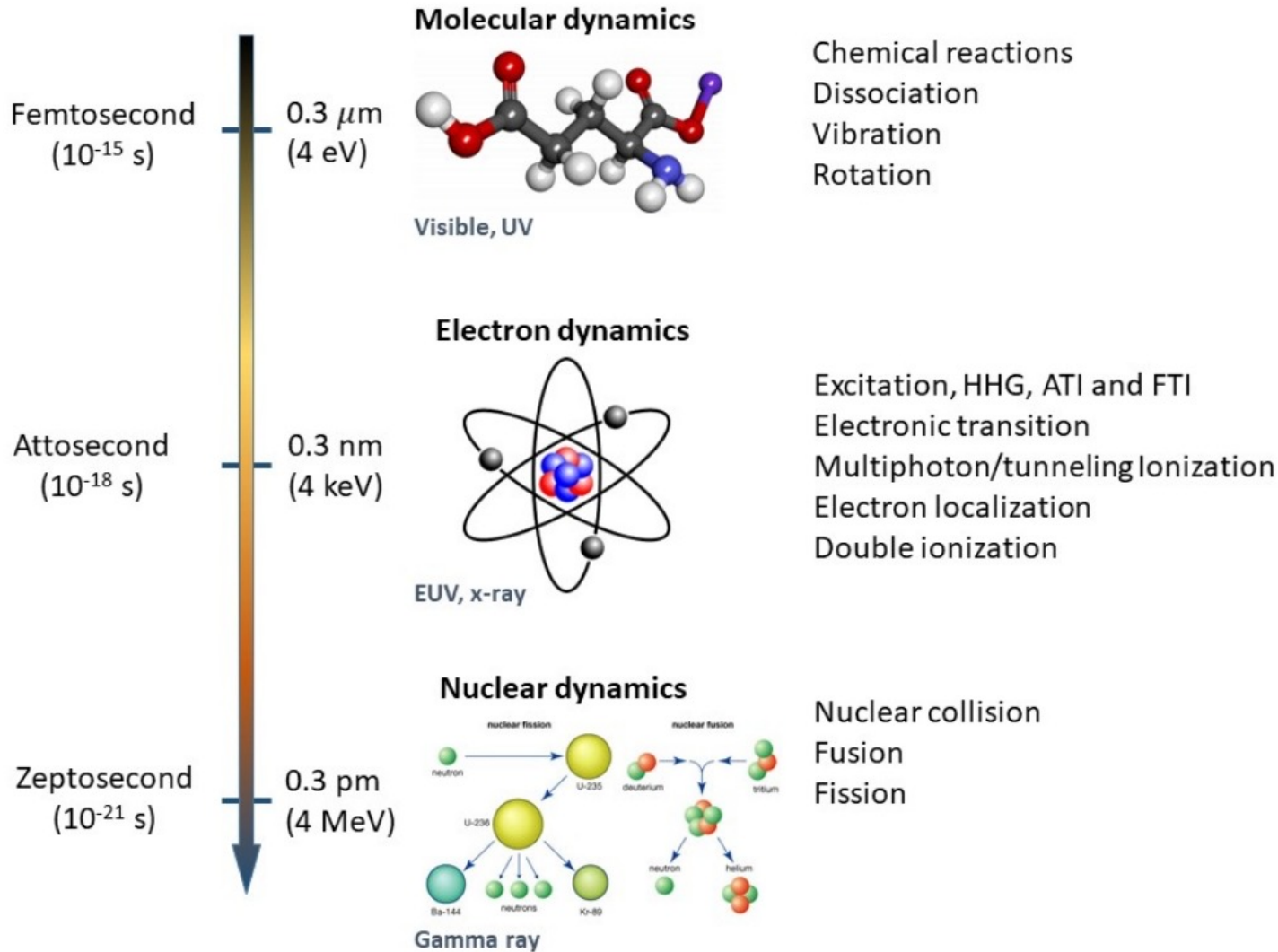
**Krzysztof Czuba**  
(Warsaw University of Technology)

Tomorrow – 16:35

# Phase & Amplitude Noise Theory

# The Importance of Phase Noise

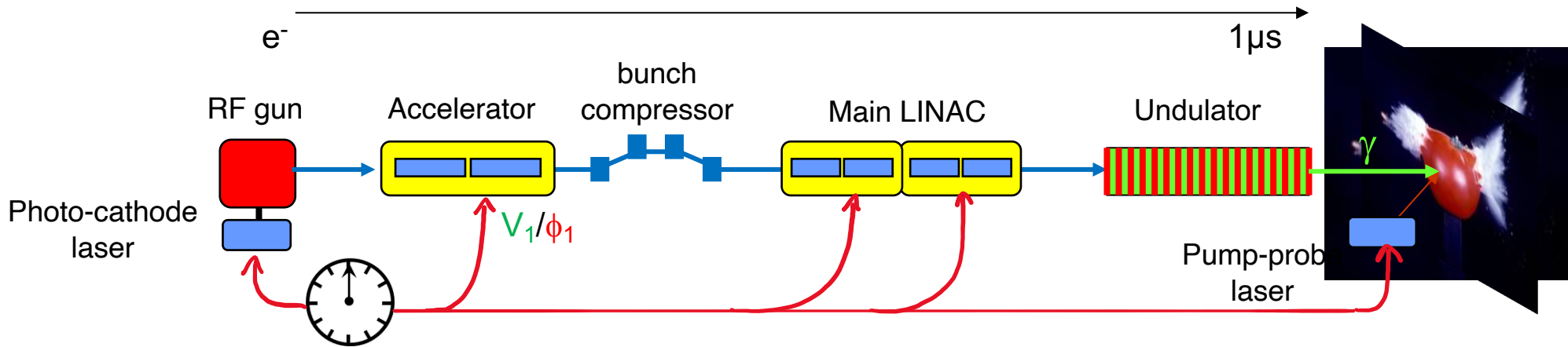
An example related to fs pump-probe experimentation with particle accelerators





# The Importance of Phase Noise

An example related to fs pump-probe experimentation with particle accelerators



Timing jitter behind BC

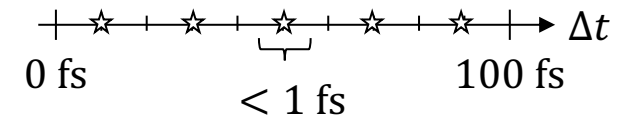
C ~5 ... 20 typically

$$\Sigma_{t,f}^2 = \underbrace{\left(\frac{R_{56}}{c_0}\right)^2 \cdot \frac{\sigma_{V_1}^2}{V_1^2}}_{\text{Voltage}} + \underbrace{\left(\frac{C-1}{C}\right)^2 \cdot \frac{\sigma_{\phi_1}^2}{\omega_{rf}^2}}_{\text{Phase}} + \underbrace{\left(\frac{1}{C}\right)^2 \cdot \Sigma_{t,i}^2}_{\text{Init. arrival}}$$

XFEL: 1.5ps/%  
FLASH: 7.0ps/%

2 ps/deg  
L-band

0.05 ps/ps  
C=20



- Bunch propagation is **absolute** measure of time.
- Phase noise accumulated over this time causes wrong ETA  $\rightarrow \frac{1 \text{ fs}}{1 \mu\text{s}} = 10^{-9}$ .
- Can estimate RF field stability requirements: **0.01% amplitude, 0.01° phase**.

# The Harmonic Oscillator

One model fits (almost) all

**Ideal** harmonic oscillation

Amplitude

Carrier frequency

$$v(t) = V_0 \cos(2\pi\nu_0 t)$$

*Phase fluctuation dominates!*

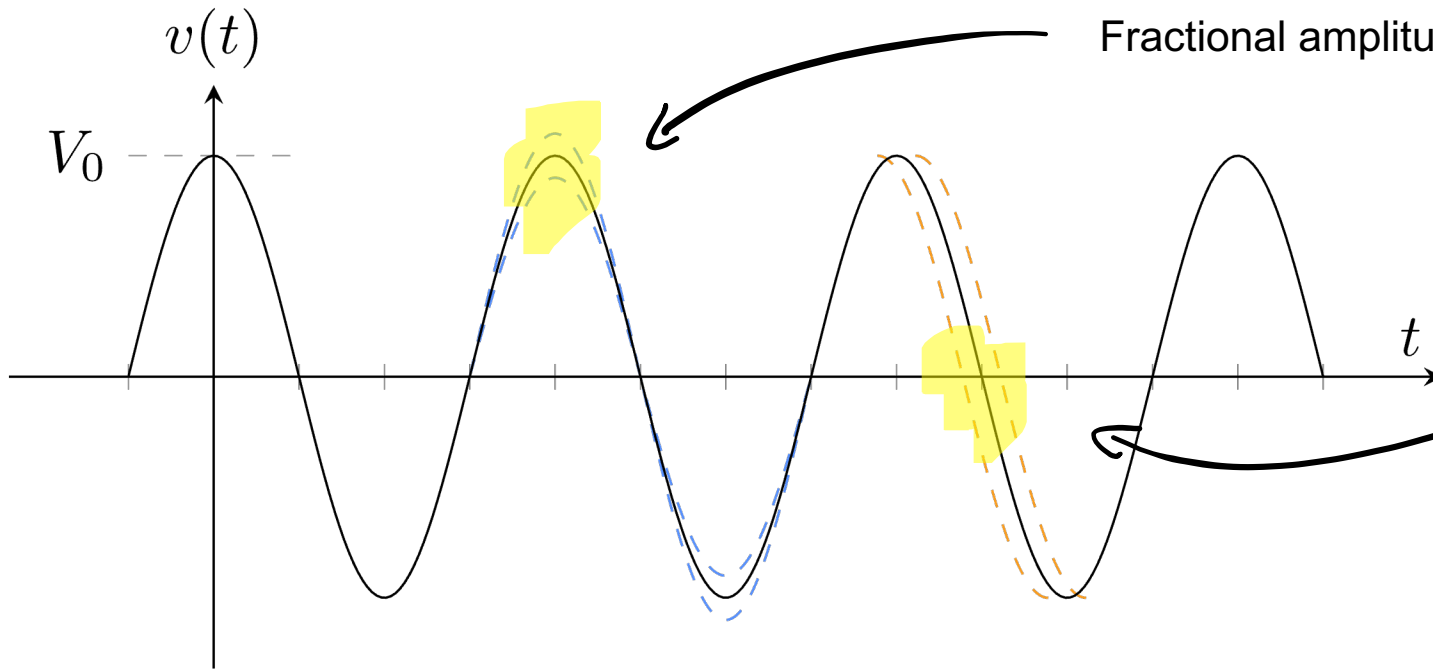
**Real** harmonic oscillation

$$a(t), \varphi(t) \ll 1$$

$$v(t) = V_0(1 + a(t)) \cos(2\pi\nu_0 t + \varphi(t))$$

Fractional amplitude fluctuation

Phase fluctuation



Timing fluctuation:  $x(t) = \frac{\varphi(t)}{2\pi\nu_0}$

# Phase & Amplitude Noise Calculations

## Timing jitter & drift

### Statistical Properties – Time Domain

- RMS phase / timing fluctuations

$$x_{\text{RMS}} = \sqrt{\frac{1}{T} \int_{-T/2}^{T/2} x(t)^2 d\tau} = \sqrt{\sigma_x^2 + \bar{x}^2}$$

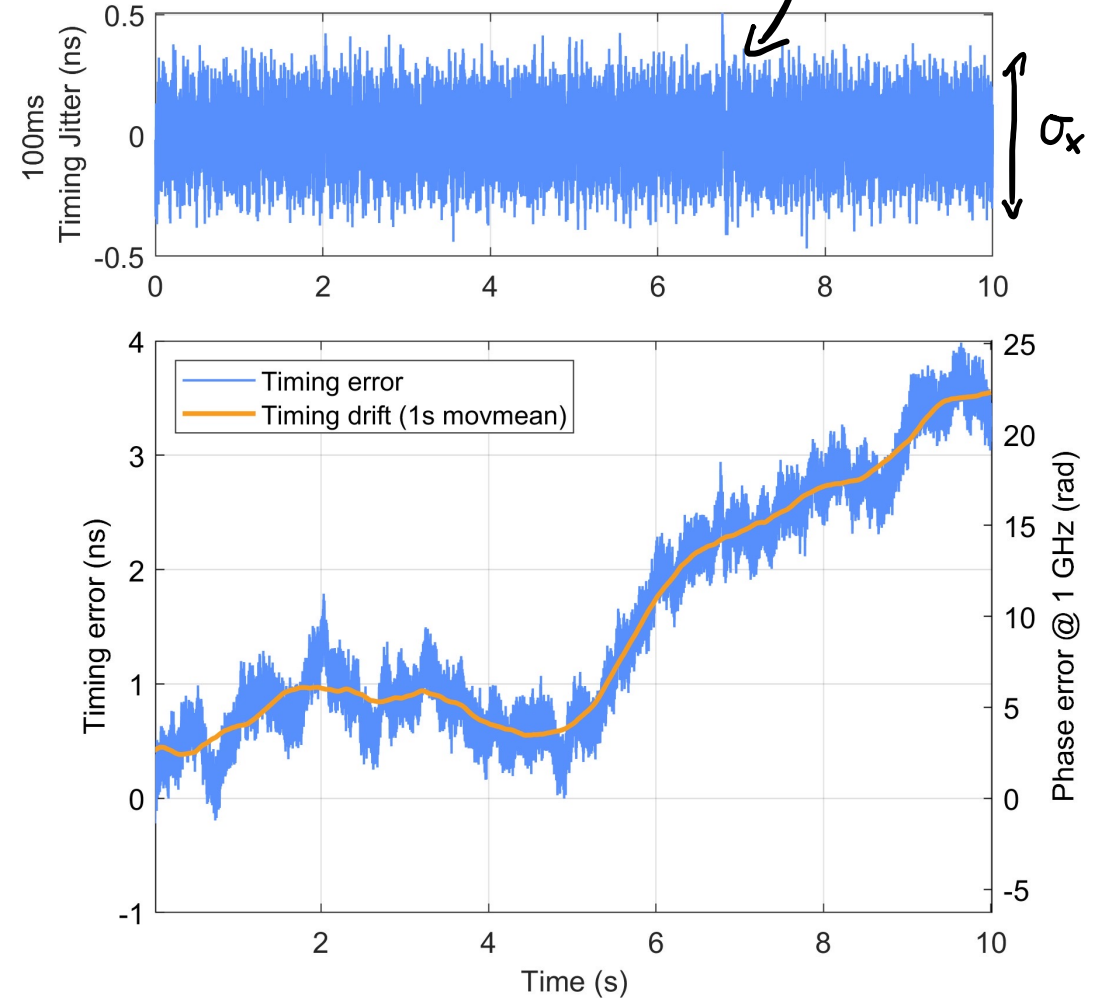
Often ignored

- Phase fluctuations are unbounded random walks.

$$\lim_{T \rightarrow \infty} x_{\text{RMS}} = \infty$$

- **Averaging Time / Bandwidth is essential!**
- Peak-to-Peak drift → “12fs pk-pk over 24h”.
- ITU definition: “Drift / Wander” > ~0.1s > “Jitter”.

Residual jitter after subtracting 100ms mov. avg.





# Phase & Amplitude Noise Calculations

## Spectral representations

### Statistical Properties – Frequency Domain

- Spectral analysis via Fourier Theory  
... but Fourier Transform is only meaningful for deterministic signals.

- **(Two-sided) power spectral density (PSD)**

$$S_{\varphi}(f) = \int_{-\infty}^{\infty} R_{\varphi}(\tau) e^{-i2\pi\tau} d\tau, \quad [S_{\varphi}(f)] = \frac{\text{rad}^2}{\text{Hz}}$$

- Auto-correlation function  $R_{\varphi}(\tau)$  not accessible  
... estimation via Wiener-Khinchin **Periodogram**:

$$S_{\varphi}(f) = \lim_{T \rightarrow \infty} \frac{1}{T} |\hat{\varphi}_T(f)|^2$$

- Real signal  $\rightarrow$  one-sided spectrum  $S'_{\varphi}(f)$  is sufficient.
- “Single-Sideband” only applies to carrier signals.

### Mathematical Rigor

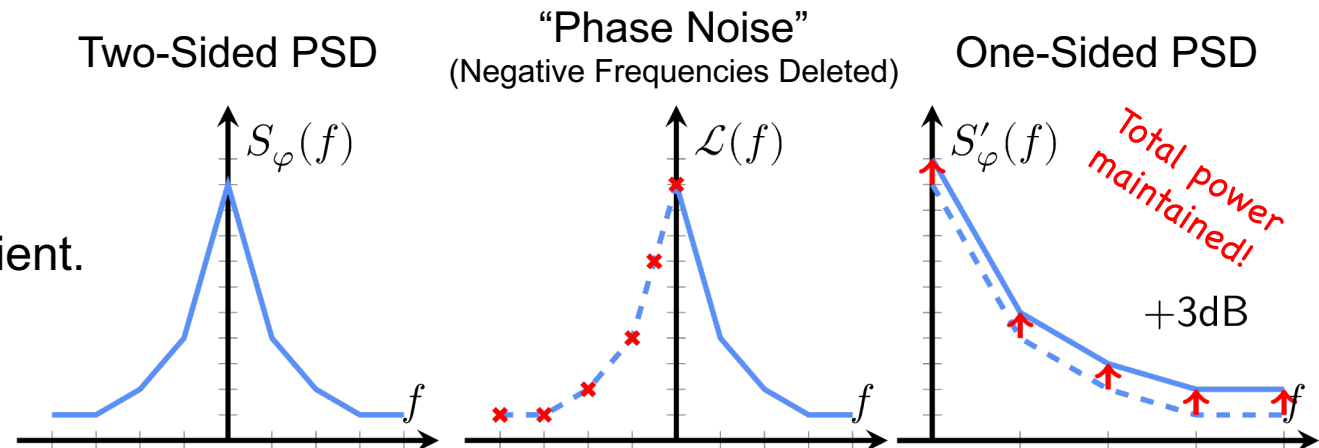
“Does Wiener-Khinchin apply?”

Process  $\varphi(t)$  must be:

- Wide-sense stationary
- Ergodic

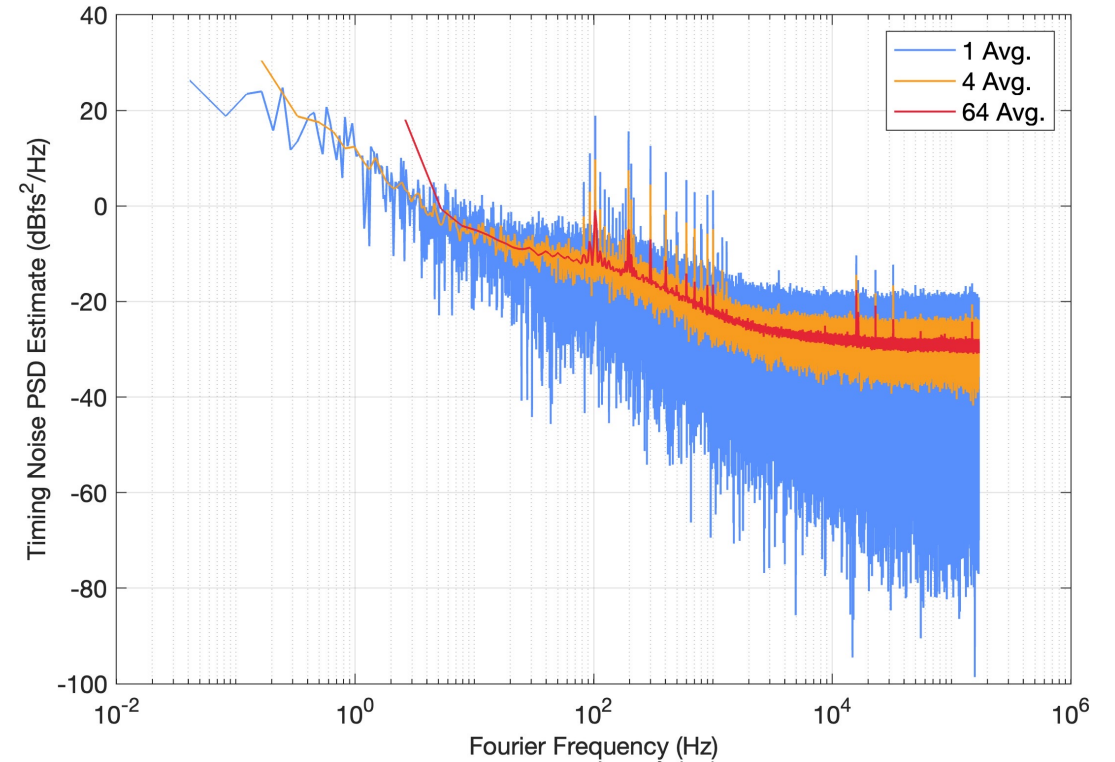
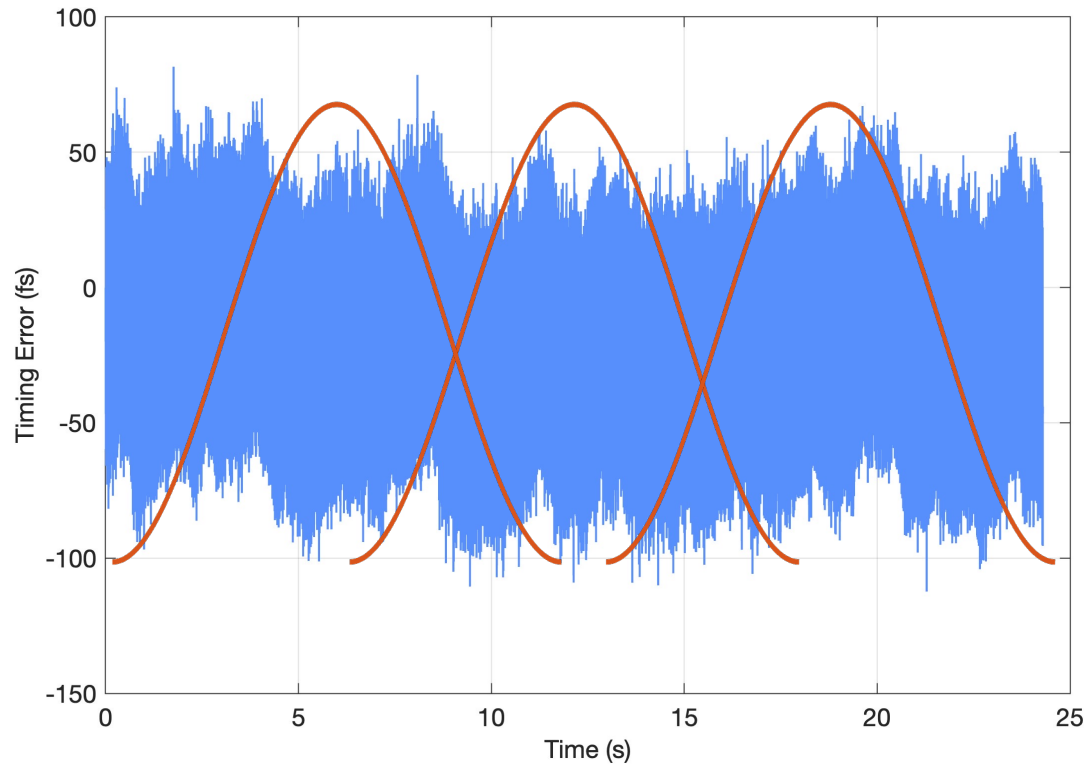
Solution:

- Only observe for a finite time and assume stationarity
- Remove phase offset at each measurement and assume ergodicity.



# Averaging in Estimation – Bartlett and Welch's Method

Improving the estimate, reducing sample variance



# Phase & Amplitude Noise Definitions (IEEE Standard 1139)

Old habits definitions die hard

## Phase Noise

- Definition since '99

$$\mathcal{L}(f) = \frac{1}{2} S'_{\varphi}(f), \quad [10 \log_{10} \mathcal{L}(f)] = \frac{\text{dBc}}{\text{Hz}}$$

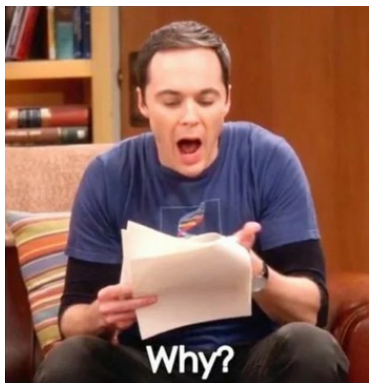
- Preferred in practice

## Amplitude Noise

- Definition since '99

$$\frac{1}{2} S'_a(f), \quad \left[ \frac{1}{2} S'_a(f) \right] = \frac{1}{\text{Hz}}$$

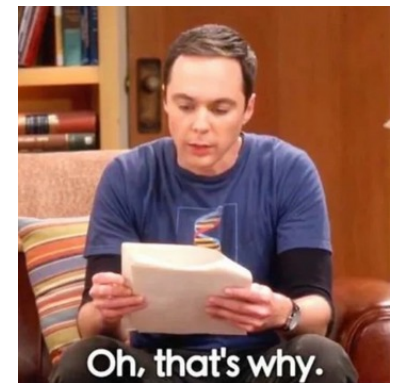
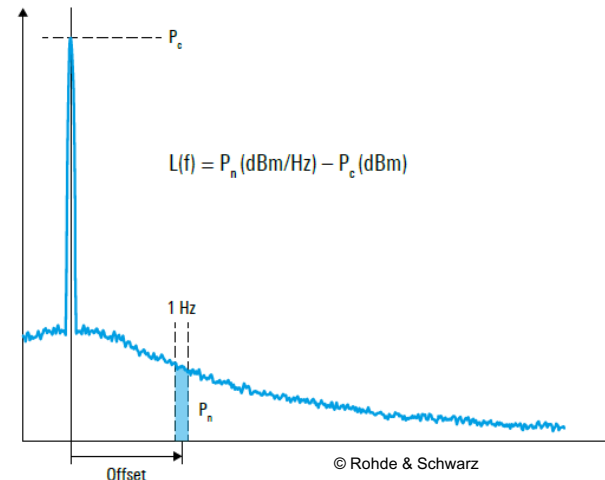
- Often also in dB / Hz



## Historical Context

Phase noise **used** to be derived from the carrier's side-lobes on an RF analyser.

- Not accurate close to the carrier.
- Does not discriminate phase and amplitude fluctuations.



# Phase & Amplitude Noise Calculations

## Integrated Jitter

### Linking Time & Frequency Domain

- Using the Plancherel Theorem, we find

$$x_{\text{RMS}} = \frac{1}{2\pi\nu_0} \sqrt{\int_0^{\infty} S'_{\varphi}(f) df} = \infty$$

- Perhaps more useful: “Integrated (Timing) Jitter”,

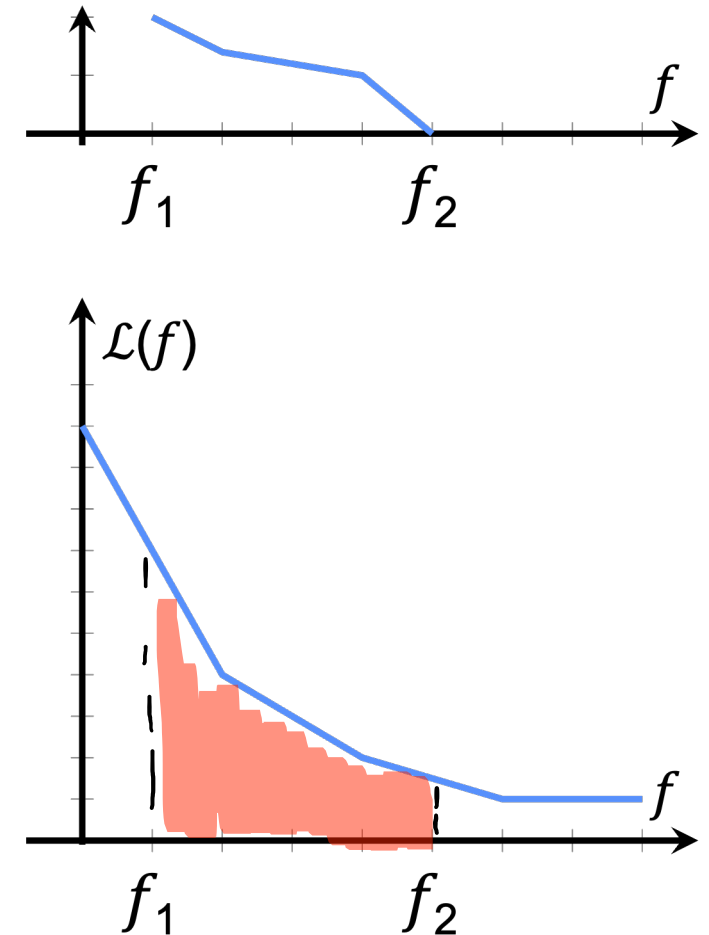
$$J_t = \frac{1}{2\pi\nu_0} \sqrt{\int_{f_1}^{f_2} S'_{\varphi}(f) df}$$

- Cumulative integrated jitter curve

$$f_1 \rightarrow f_2, \quad \text{or,} \quad f_2 \rightarrow f_1$$

- Always state integration bounds!

Integrated Jitter (fs)



# Phase & Amplitude Noise Calculations

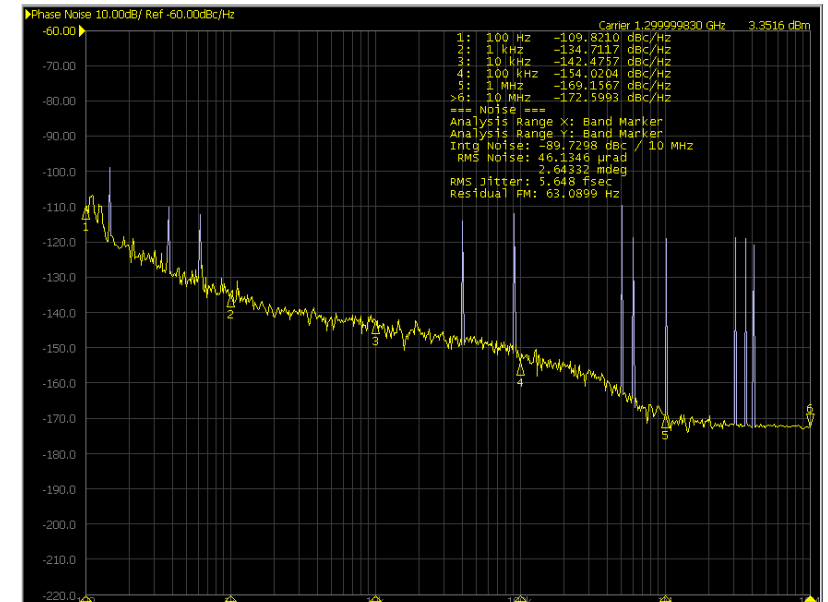
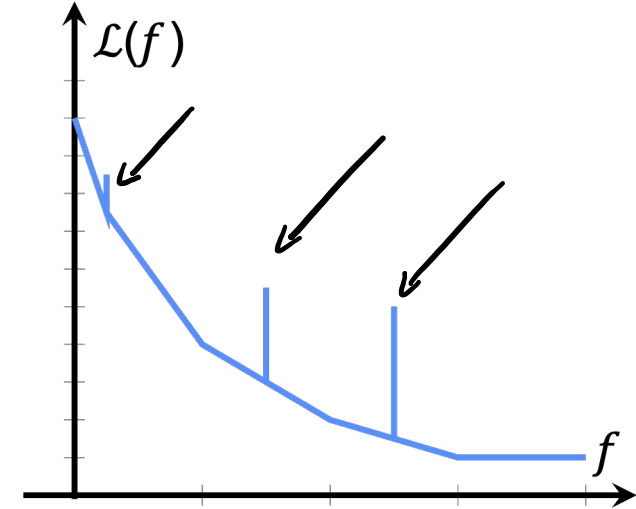
## Spurious Content

### Handling the discrete & deterministic

- Non-random disturbances cause narrow spikes = “Spurs”.
- Jitter adds in root-sum-square.

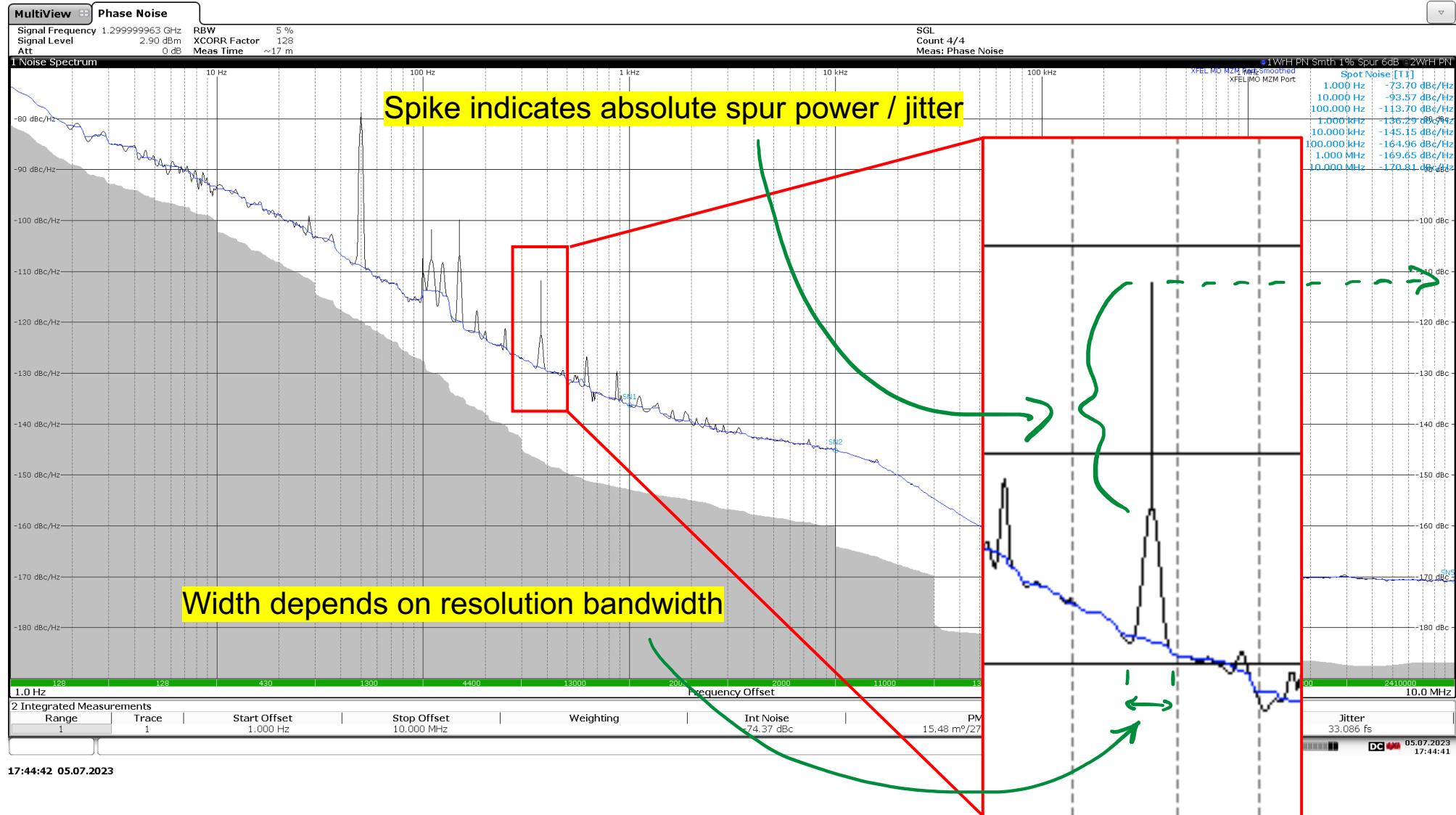
$$J_t = \sqrt{J_{t,\text{smooth}}^2 + J_{t,\text{spur1}}^2 + \dots + J_{t,\text{spurN}}^2}$$

- Same as integrating over “Spurs in dBc / Hz” trace.
- Beware: Display on analysers varies!



# Spurious Content

## An example from the FSWP analyser





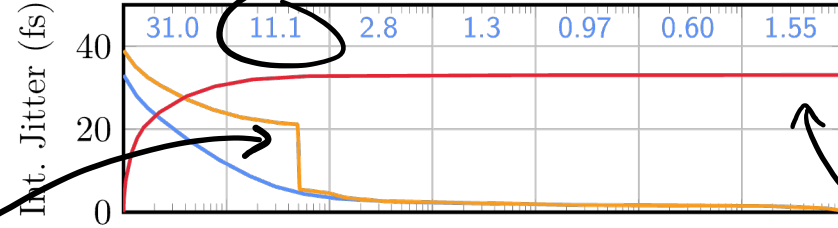
# Noise Plots

## Do's & Don'ts

- Clearly declare omitted spurs.
- Avoid non-standard units.
- Use caption to clarify measurement conditions.

- There is no one-fits-all solution.

Decade jitter

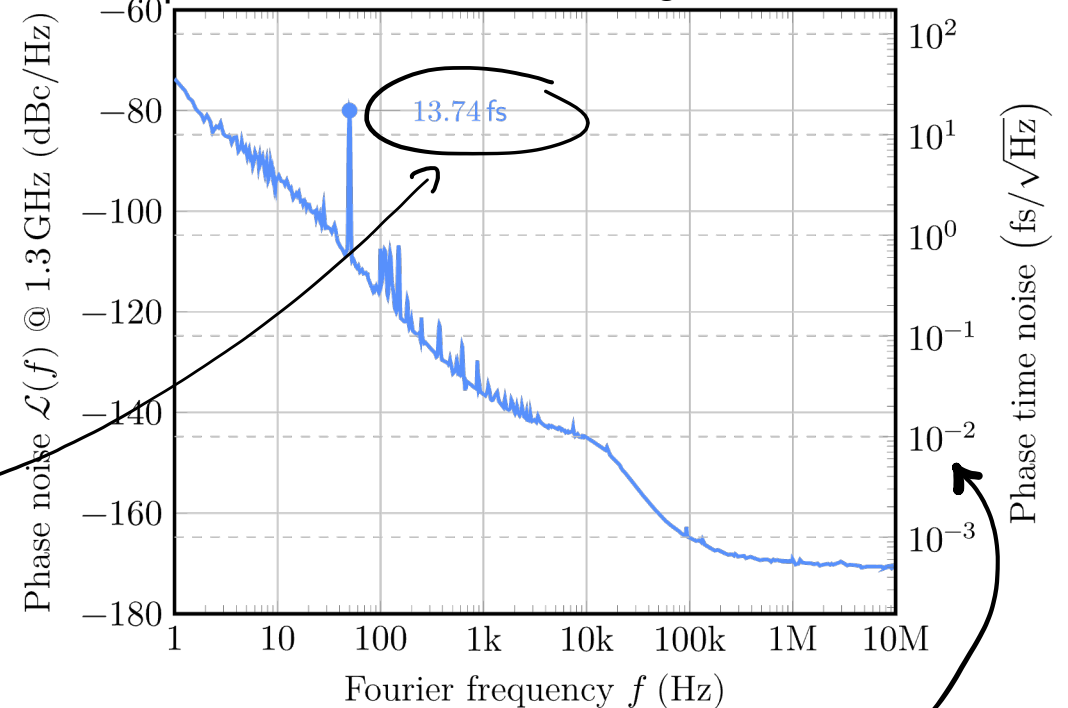


Integrate with / without spurs

Integrate in sensible direction

Clearly indicate carrier

Label significant spurs



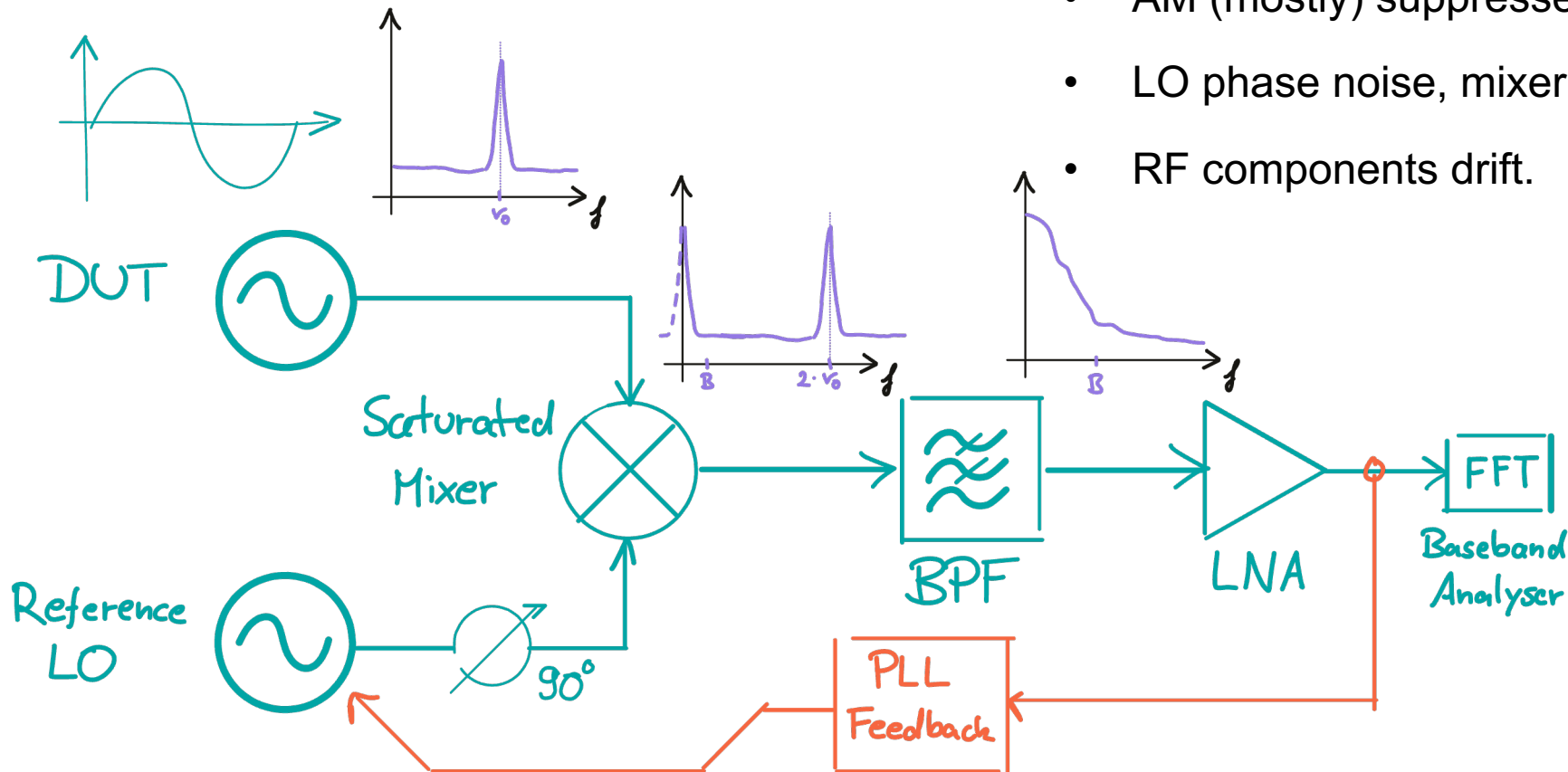
Use second axis for alt. units, spur jitter or integrated jitter

# Phase & Amplitude Noise Measurement Techniques

# Phase Noise Measurements

## Saturated Mixer

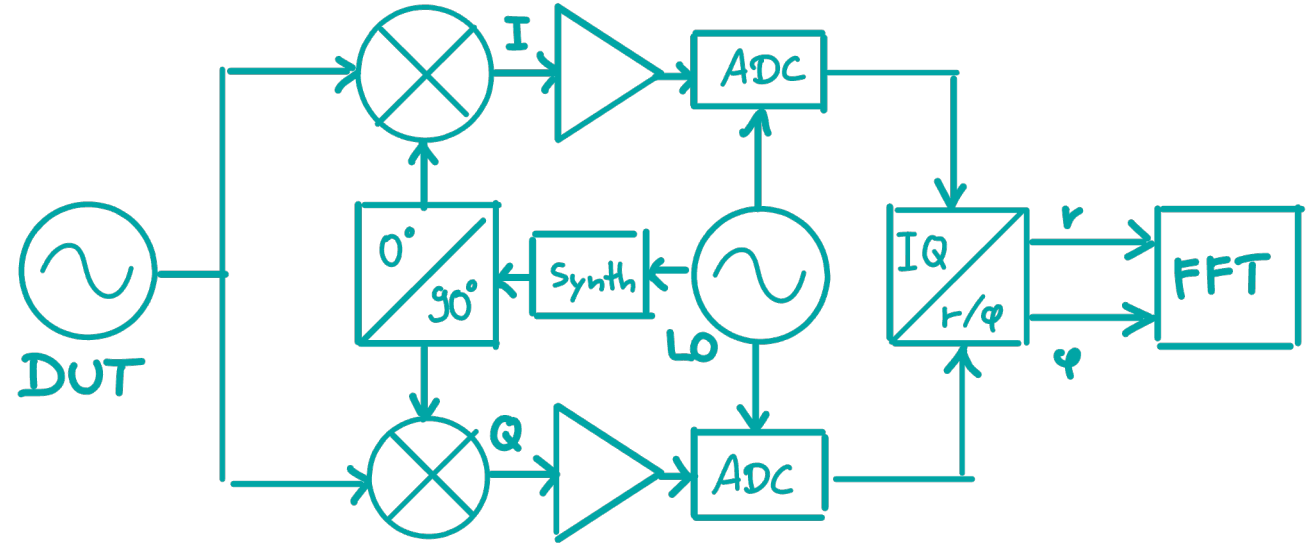
- Mixing in quadrature with LO @  $\nu_0$  yields zero-IF.
- Only linear in small angle approximation  
→ only for small PM.
- Low bandwidth PPL to LO ensures zero-IF.  
→ PLL response needs to be taken into account!
- AM (mostly) suppressed.
- LO phase noise, mixer & LNA flicker added to DUT noise.
- RF components drift.



# Phase Noise Measurements

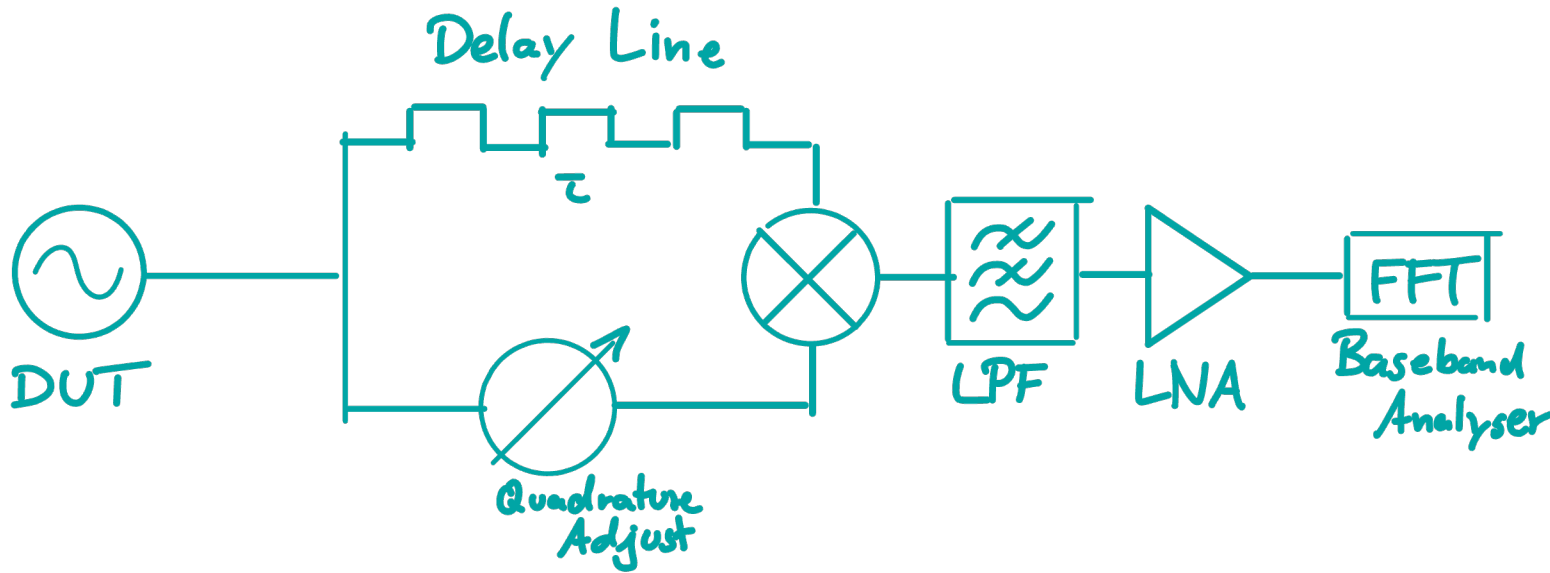
## I/Q Detection

- Dual saturated mixer, in-phase + quadrature.
- Demodulation:  $\varphi = \tan^{-1} \frac{Q}{I}$ ,  $a = \frac{\sqrt{I^2 + Q^2}}{A} - 1$ .
- Not reliant on small angle approximation.
- I/Q calibration necessary.
- LO derived ADC clock allows for phase-coherent IF sampling  
→ Better harmonic disturbance rejection.
- Closer to a 360° phase detection system needed by LLRF controls.

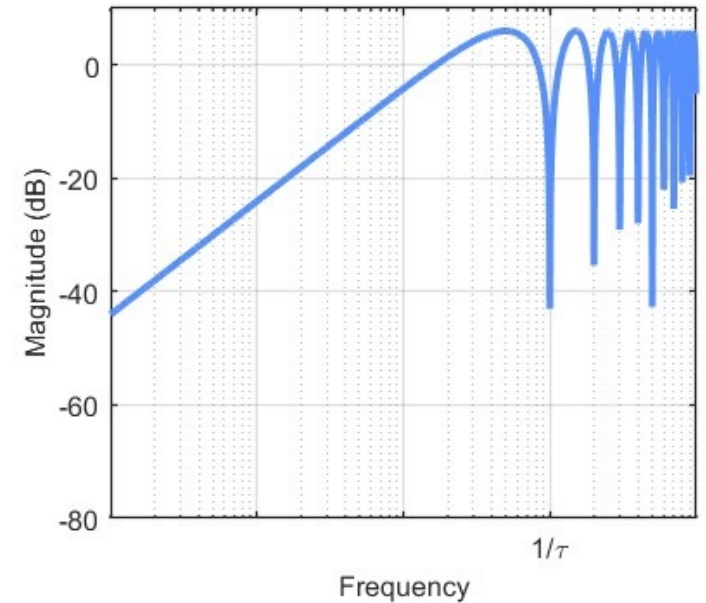


# Phase Noise Measurements

## Frequency Discriminator Method



$$\varphi(t) - \varphi(t - \tau) \rightarrow |1 - e^{-i2\pi f\tau}|^2 S_\varphi(f)$$



- Self-referenced, no LO.
- Delay line loss  $\rightarrow$  better for optical.
- Delay line drifts.
- Low sensitivity / SNR for slow DUT phase drifts.
- Elimination at  $f = N/\tau \rightarrow$  limited frequency range.

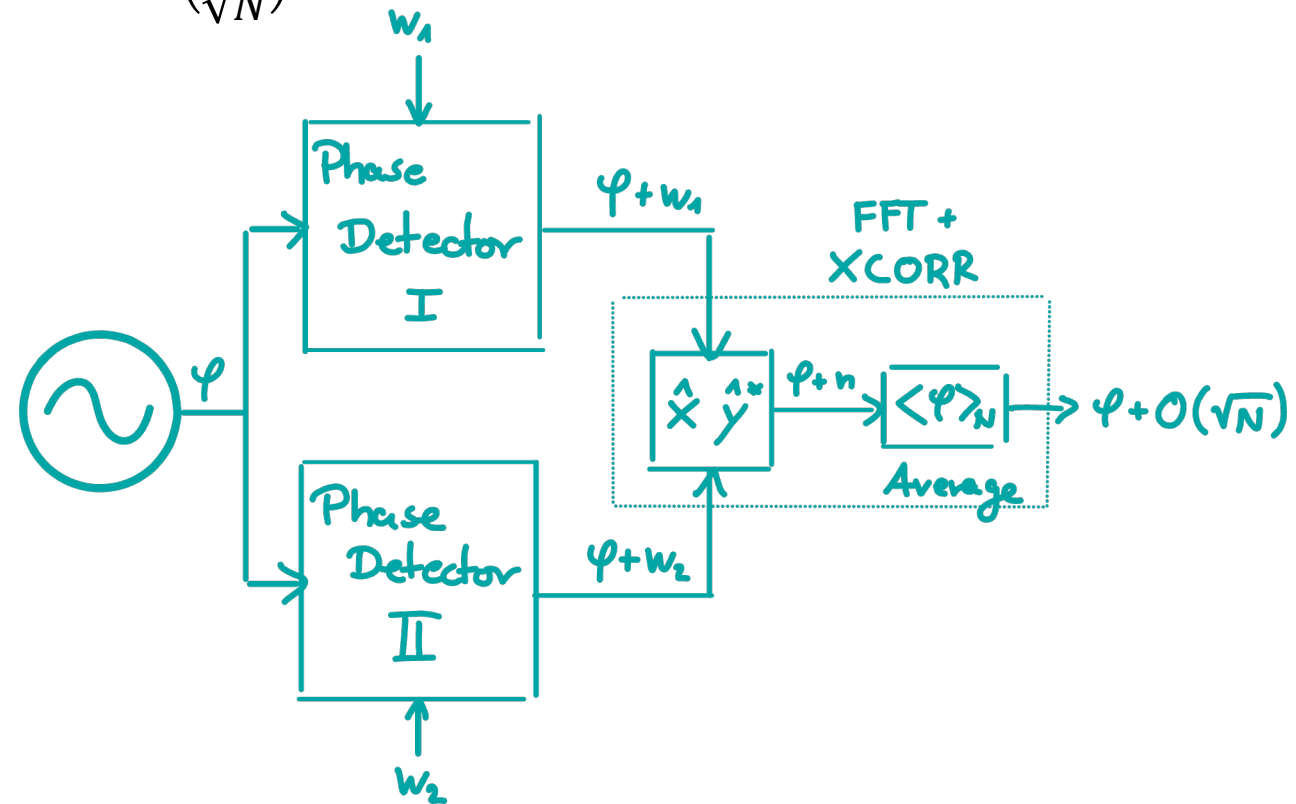
# Improving Phase Noise Measurements

## Cross-Correlation Techniques

- Cross-correlation is convolution in TD, i.e. multiplication in FD:

$$\text{XCORR}(\varphi + w_1, \varphi + w_2) = (\varphi + w_1) \star (\varphi + w_2) = \bar{\hat{\varphi}} \cdot \hat{\varphi} + O\left(\frac{1}{\sqrt{N}}\right)$$

- Phase detector noise scales with  $\frac{1}{\sqrt{N}}$ 
  - -3 dB @ N = 4
  - -15 dB @ N = 1024.
- Sample variance shrinks at the same time.
- Common noise not suppressed (e.g. AM).
- Cross-spectral breakdown for phase inverted common noise!

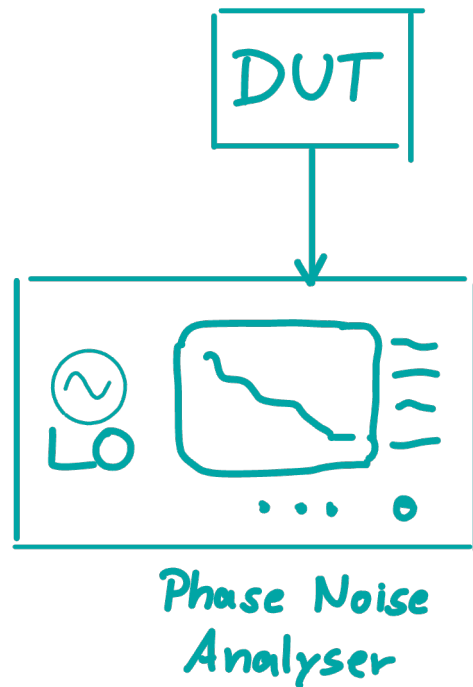




# Absolute, Residual and Additive Measurements

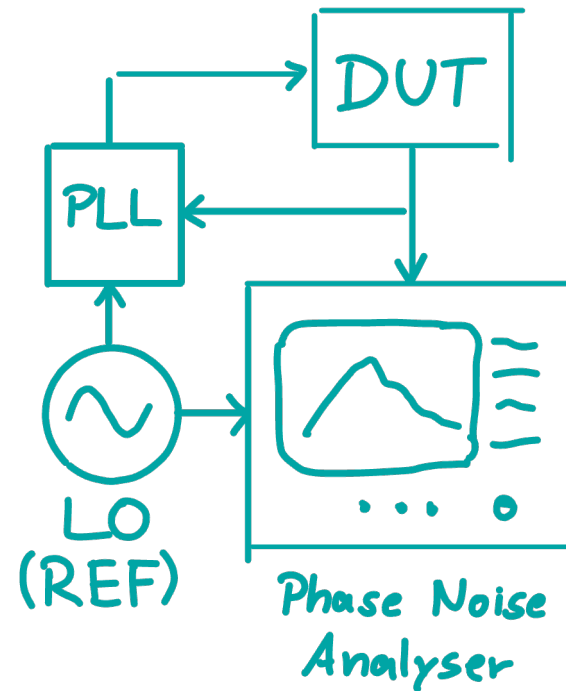
## Absolute

- Stability of an oscillator
- Analyser LO better than DUT (or XCORR)



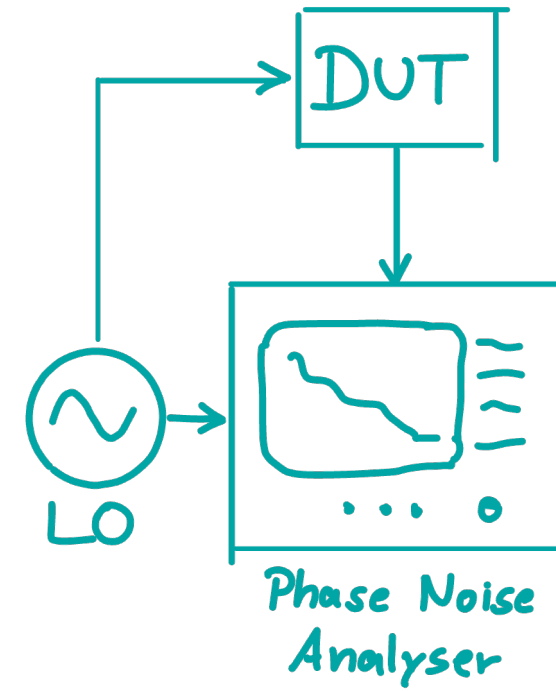
## Residual

- Locking performance of PLL
- Reference as ext. analyser LO



## Additive

- Excess noise of components
- Int. or ext. analyser LO



# Phase Noise Analysers

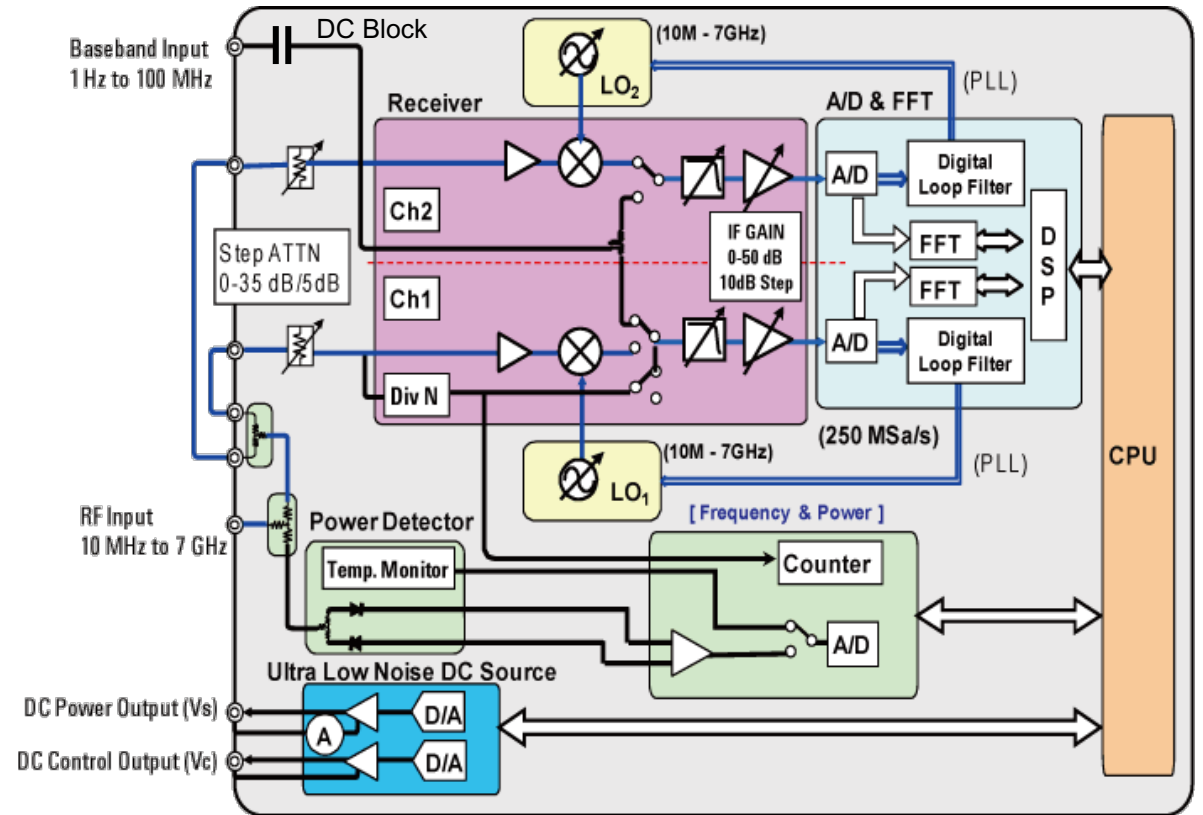
# Phase Noise Analysers

## Agilent / Keysight E5052B

- Double saturated mixer scheme
- Found in many labs, weighs a ton.
- Important settings:
  - Attenuation (ideally 0-5 dBm after att.)
  - IF Gain (as high as possible without saturation error)
  - XCORR (double until PN doesn't improve anymore)
  - LO optimization, Capture range "normal"
- $\pm 35V / 50 \text{ Ohm}$  baseband input (DC block capacitor)
- Careful: Baseband shows  $V/\text{Hz}$ , but really is  $V/\sqrt{\text{Hz}}$ !
- (now superseded by SSA-X series)



© Keysight

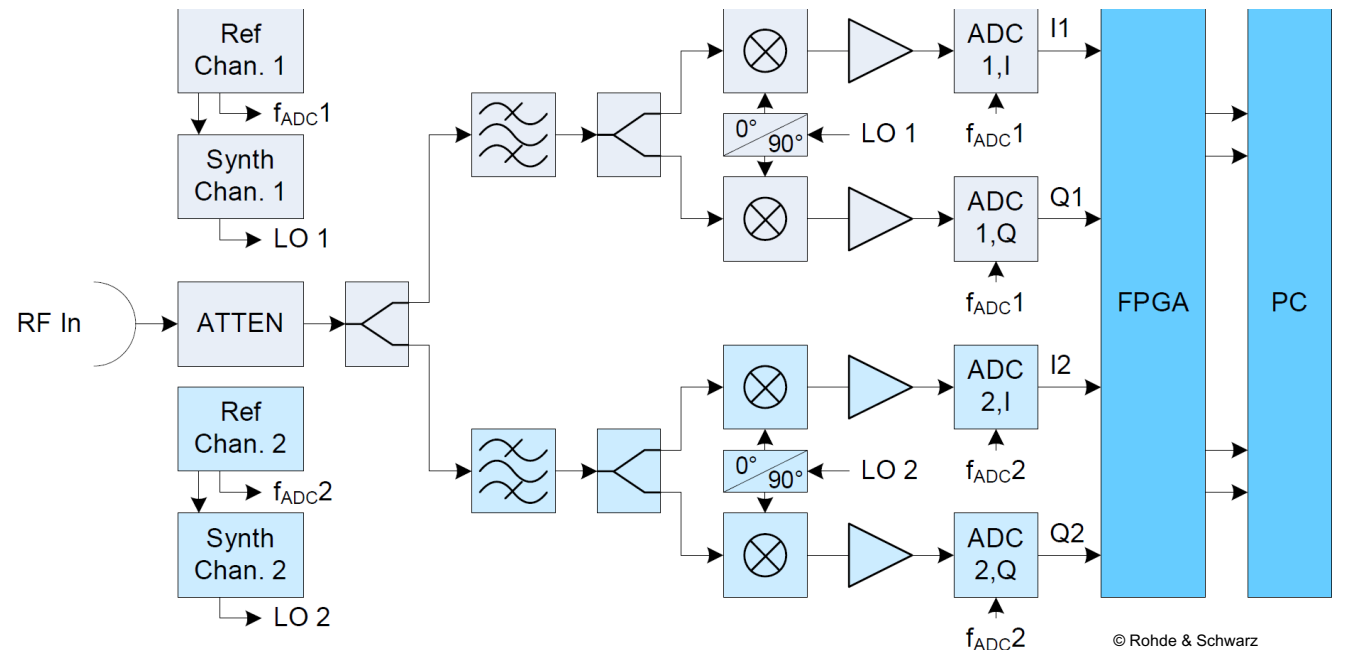


ssa0207 © Keysight

# Phase Noise Analysers

## Rohde & Schwarz FSWP / FSPN

- Double I/Q-detection scheme
- Non-zero IF leads to less distortion, no PLL
- Important settings:
  - Resolution Bandwidth (5%, 2%, 1% are common)
  - XCORR (aim for 10dB headroom to device sensitivity)
- Useful: Auto-Setup, fast, sensitivity indicator
- $\pm 2V / 50 \text{ Ohm}$  baseband input
- Pulsed measurements  
(bandwidth limited to  $f_{\text{pulse}}/2$ )



# Practical Measurement Considerations



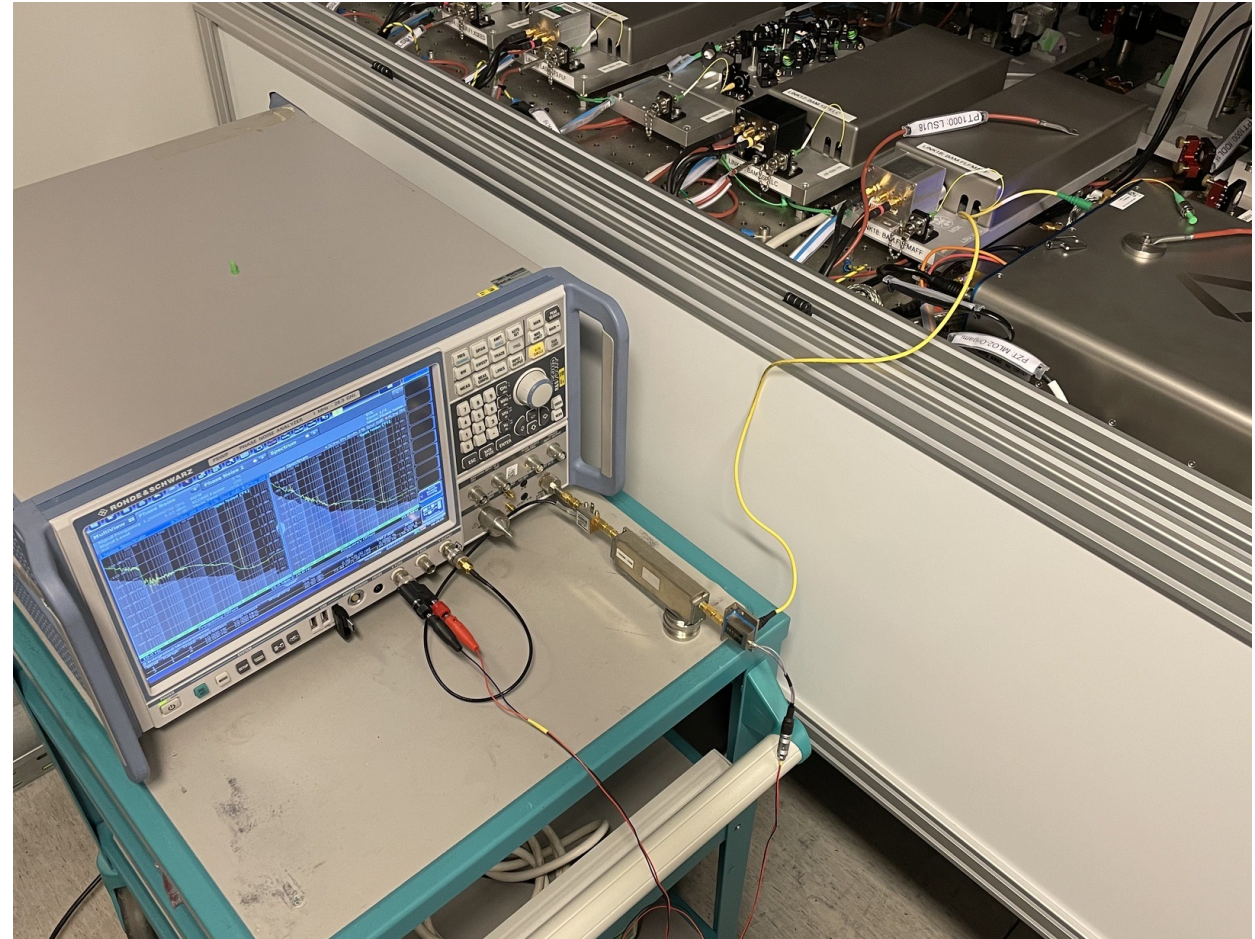
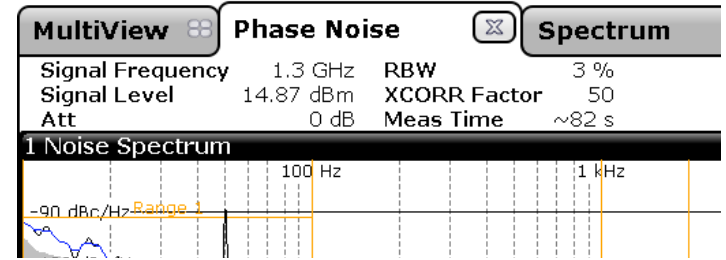
# Proper Documentation is Key

A few minutes can save hours of work

- Measurements are worthless without measurement conditions – which you **will** forget.
- Keep screenshot, showing device settings.
- Store as many info as possible in trace file.
- A photo takes just two seconds.
- Use presets for consistent measurements.
- Note down external factors (PLL settings, optical power, LNA supply voltage, ...).

## Beware:

- Ground-loops, unshielded cables, bad soldering, broken / unreliable components, sufficient signal power, power grid disturbances.

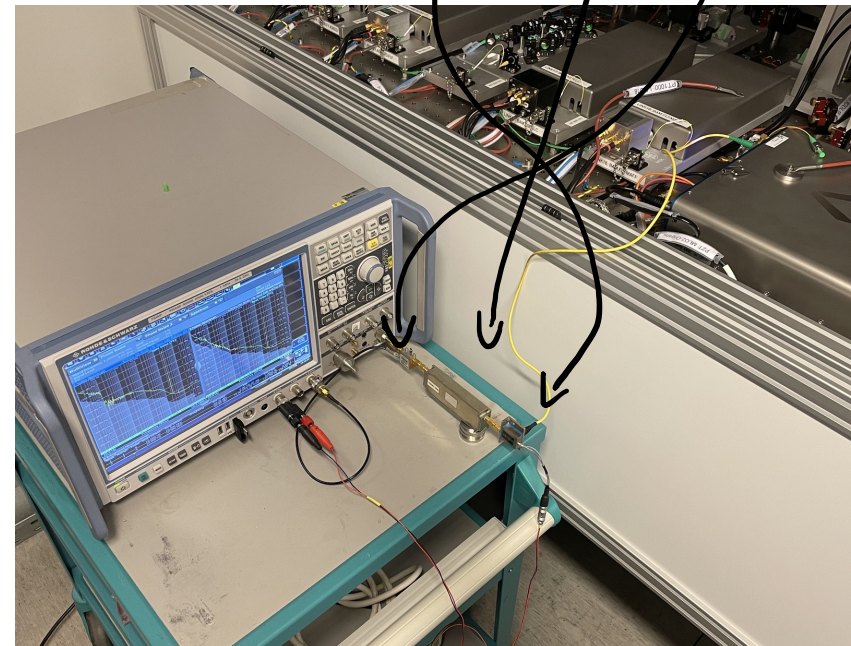
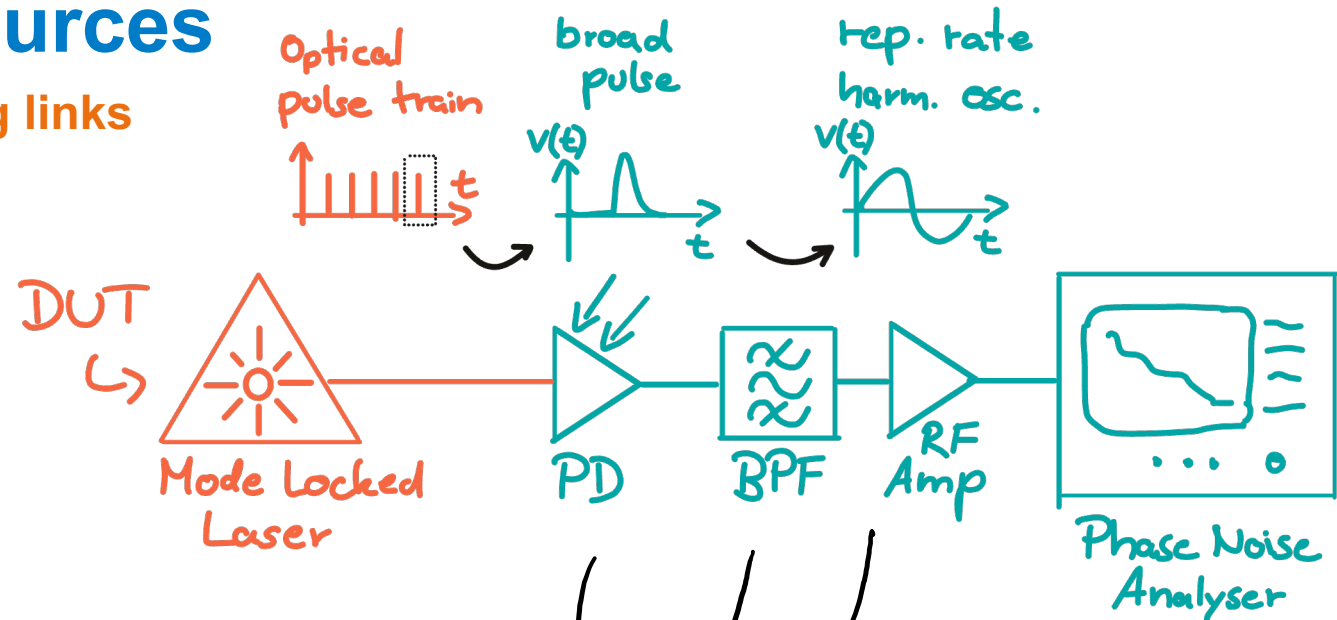




# Measurements on Optical Sources

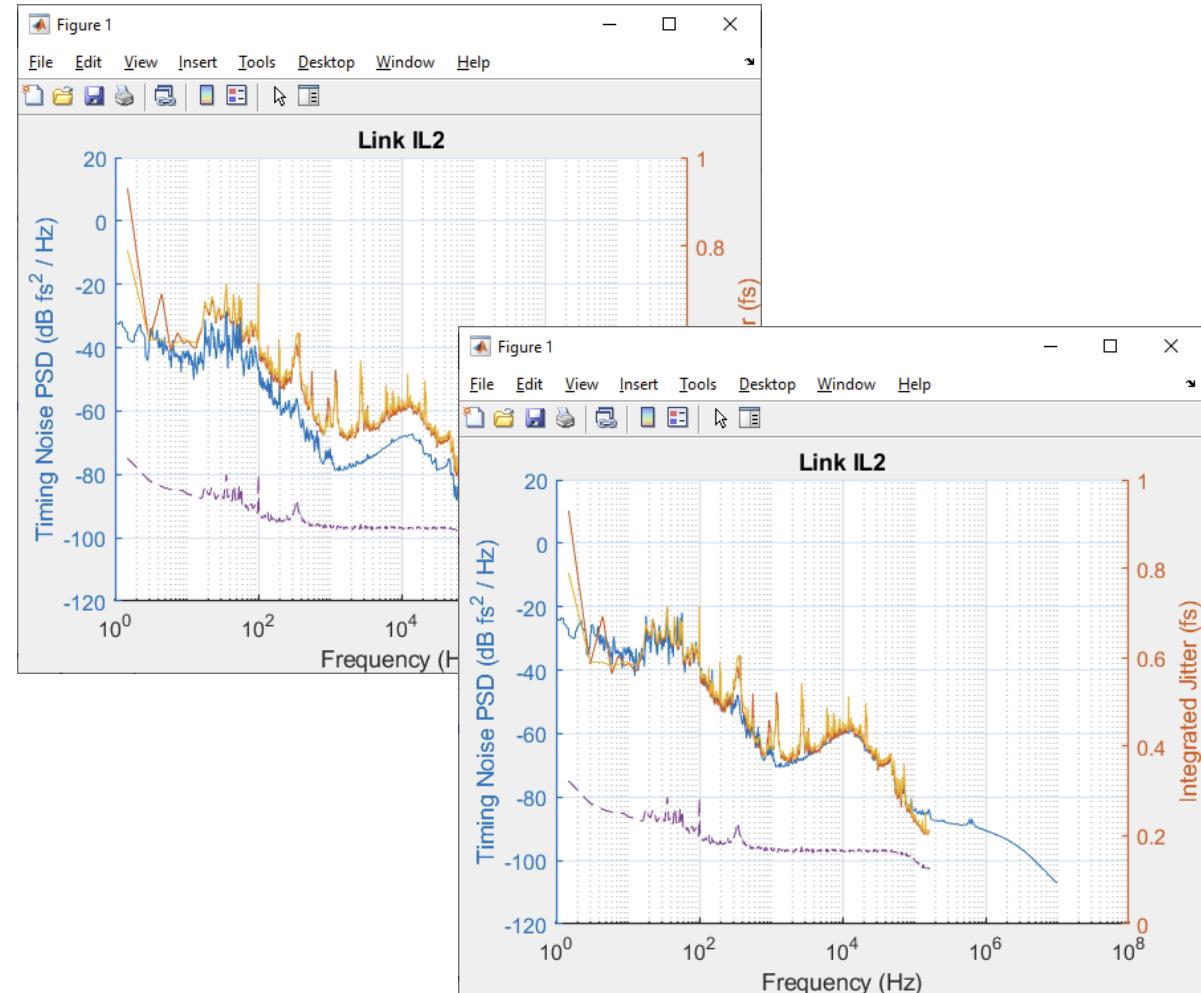
## Mode-locked lasers & Pulsed optical fibre timing links

- Free-running MLL are “drifting sources”.  
→ Generally unreliable below 10 Hz offset.
- Understand your detection chain:
  - Photodiode AM/PM dominates after ~ 1-10 kHz.
  - Amplifier excess noise
- 50 Ohm system, PD properly terminated?
- Photodiode bias voltage and amplifier supply voltage ideally from analyser (ground loops).
- Analyser itself can be the disturbance source!
  - Heat
  - EMI (Spurious)



# Baseband Measurements / External Phase Detectors

- Useful for:
  - Power supply noise (careful HV!)
  - External phase detectors
  - Relative intensity noise
- Standard units  $\frac{V}{\sqrt{\text{Hz}}}$  displayed in dB. But:
$$20 \log_{10} \left[ \frac{V}{\sqrt{\text{Hz}}} \right] = 10 \log_{10} \left[ \frac{V^2}{\text{Hz}} \right]$$
- Watch out for impedance mismatches!
- Correlation measurements only possible with certain devices.
- Ground-loops are critical! Use isolation transformer.
- Very sensitive, even to “swinging” cables.



# Measuring at the Limit

## Problems & Physical Boundaries

- Mechanical Stability

$$-180 \text{ dB rad} \rightarrow 4 \cdot 10^{-12} \text{ m}$$

- Theoretical DUT thermal noise floor at (300K, > 1kHz offset from carrier)

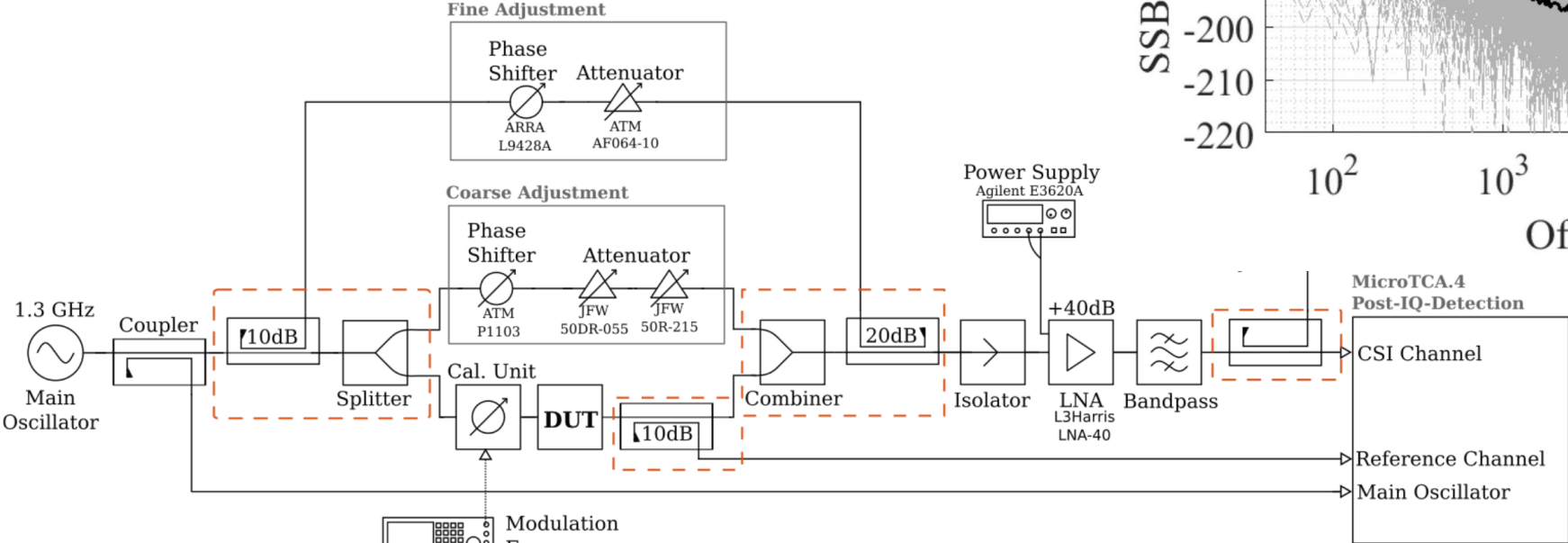
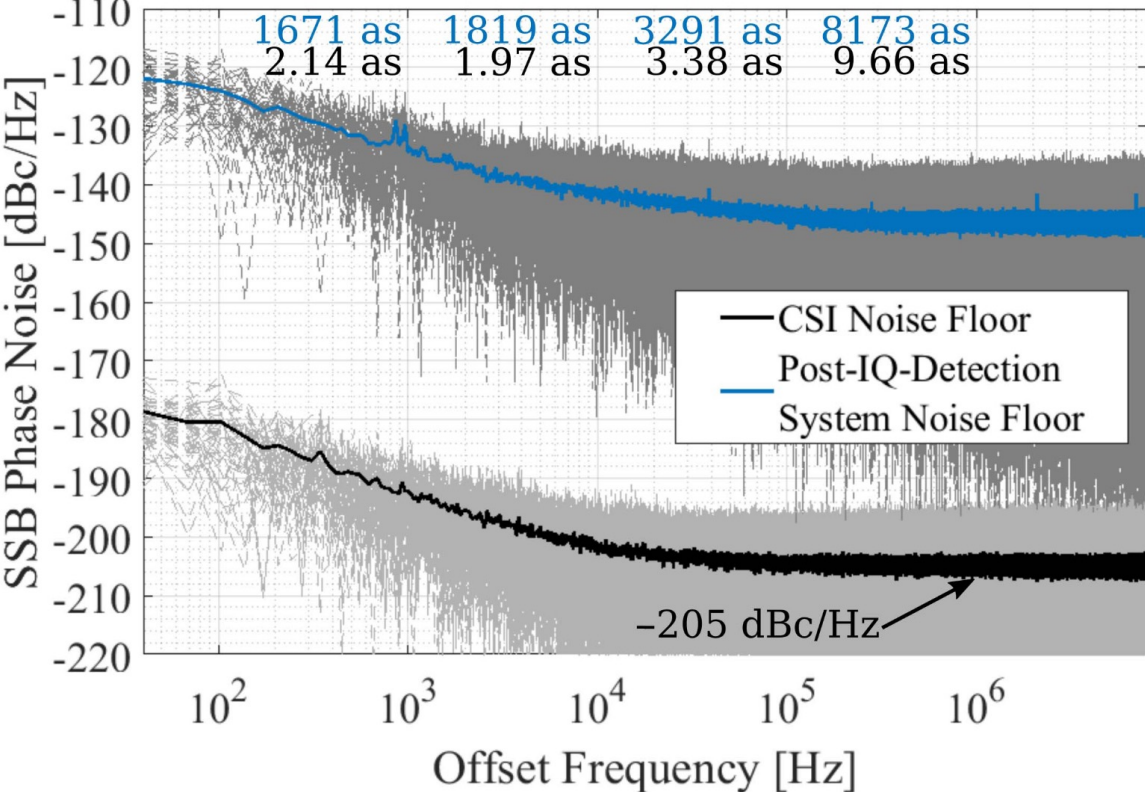
$$-177 \frac{\text{dBc}}{\text{Hz}} - P_{\text{carrier}}$$

- Cross-correlations do not help indefinitely  
(exponential measurement time, numerical problems, cross-spectrum collapse).
- “Close to the carrier”, analyser sensitivity is limited by RF component flicker in the receiver.
- Harmonic distortion during down-conversion & ADC sampling.
- Baseband is noisy!



# Measuring at the Limit via Carrier Suppression Interferometry

- Mixing moves carrier power to DC
- Carrier suppression interferometry deletes carrier power
- No additive 1/f flicker when amplifying!
- Springer et al. - Phase Noise Measurements for L-Band Applications at Attosecond Resolution



# References & Further Reading

For the serious phase noise enthusiast

## Theory

- Demir – “Phase Noise in Oscillators A Unifying Theory and Numerical Methods for Characterisation” (1998)
- Rubiola – “Phase Noise and Frequency Stability in Oscillators”, Cambridge University Press (2009) (and other works)
- Da Dalt – “Understanding Jitter and Phase Noise”, Cambridge University Press (2018)
- Gardner – “Phaselock Techniques”, Wiley, 3<sup>rd</sup> ed. (2005)

## Practice

- Rubiola – Slides from [rubiola.org](http://rubiola.org)
- Rohde & Schwarz – “Understanding Phase Noise Measuring Techniques”
- NIST – various resources and papers

# Thank you!

# Questions?

## Contact

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- MSK LbSync Team: Sebastian Schulz, Thorsten Lamb, Matthias Felber, et al.